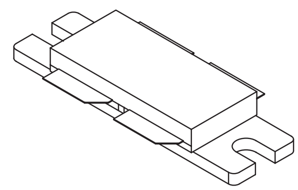
The RF MOSFET Line
RF Power Field-Effect Transistor
N–Channel Enhancement–Mode Lateral MOSFET

MRF186

Designed for broadband commercial and industrial applications at frequencies from 800 MHz to 1.0 GHz. The high gain and broadband performance of this device makes it ideal for large–signal, common source amplifier applications in 28 volt base station equipment.

- Guaranteed Performance @ 960 MHz, 28 Volts
  Output Power — 120 Watts (PEP)
  Power Gain — 11 dB
  Efficiency — 30%
  Intermodulation Distortion — –28 dBc
- Excellent Thermal Stability
- 100% Tested for Load Mismatch Stress at all Phase Angles with 5:1 VSWR @ 28 Vdc, 960 MHz, 120 Watts CW

120 W, 1.0 GHz, 28 V
LATERAL N–CHANNEL
BROADBAND
RF POWER MOSFET



CASE 375B–02, STYLE 2

MAXIMUM RATINGS (2)

Rating	Symbol	Value	Unit
Drain–Source Voltage	V_{DSS}	65	Vdc
Drain–Gate Voltage (R_{GS} = 1 MΩ)	V_{DGR}	65	Vdc
Gate–Source Voltage	V_{GS}	±20	Vdc
Drain Current — Continuous	I_D	14	Adc
Total Device Dissipation @ T_C = 70°C Derate above 70°C	P_D	162.5 1.25	Watts W/°C
Storage Temperature Range	T_{stg}	– 65 to +150	°C
Operating Junction Temperature	T_J	200	°C

THERMAL CHARACTERISTICS (2)

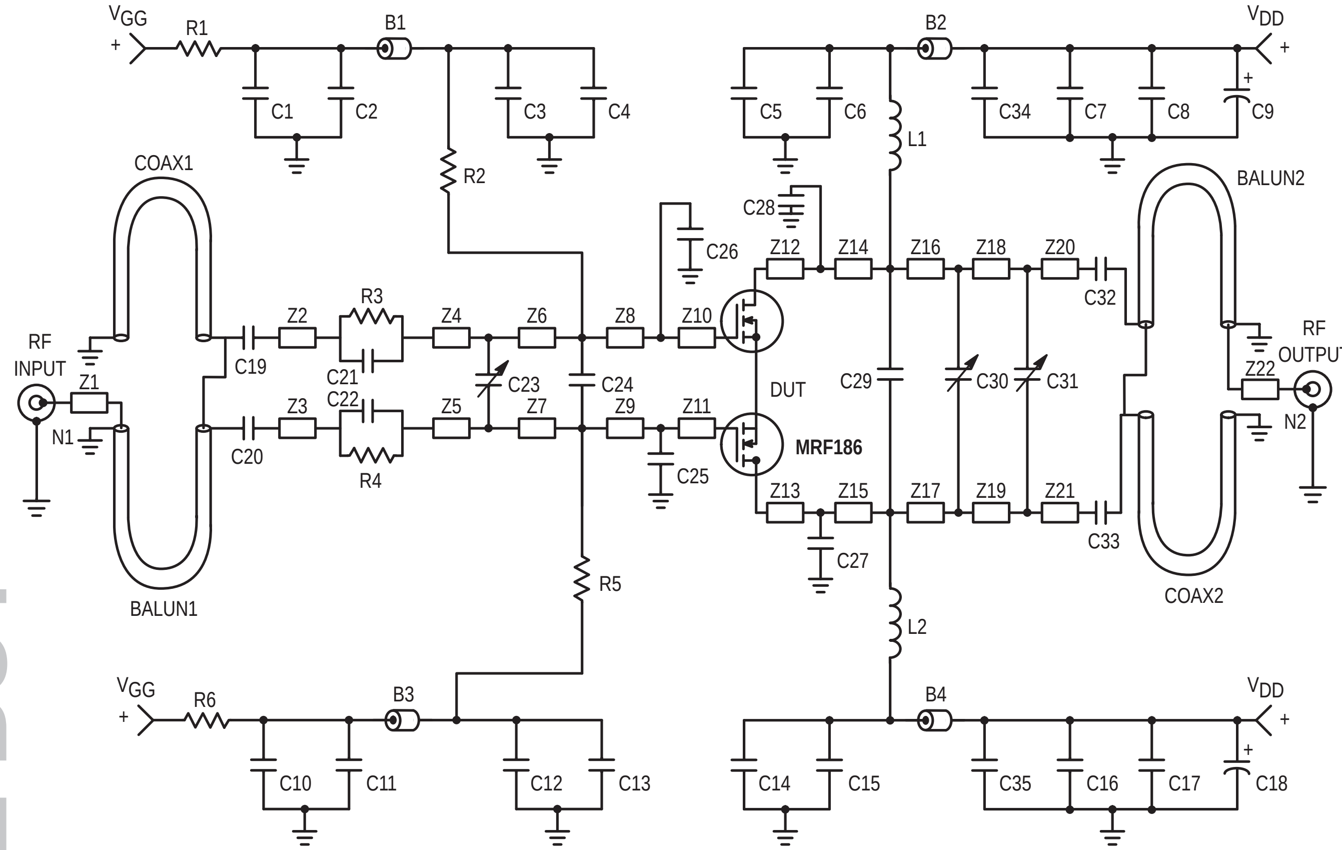
Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	0.8	°C/W

NOTE – **CAUTION** – MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS (1)					
Drain–Source Breakdown Voltage (V_{GS} = 0 Vdc, I_D = 50 μAdc)	$V_{(BR)DSS}$	65	—	—	Vdc
Zero Gate Voltage Drain Current (V_{DS} = 28 Vdc, V_{GS} = 0)	I_{DSS}	—	—	1	μAdc
Gate–Source Leakage Current (V_{GS} = 20 Vdc, V_{DS} = 0)	I_{GSS}	—	—	1	μAdc
ON CHARACTERISTICS (1)					
Gate Quiescent Voltage (V_{DS} = 26 Vdc, I_D = 300 μAdc Per Side)	$V_{GS(th)}$	2.5	3	4	Vdc
Gate Quiescent Voltage (V_{DS} = 26 Vdc, I_D = 300 mAdc Per Side)	$V_{GS(Q)}$	3.3	4.2	5	Vdc
Delta Gate Threshold Voltage (Side to Side) (V_{DS} = 28 V, I_D = 300 mA Per Side)	$\Delta V_{GS(Q)}$	—	—	0.3	Vdc
Drain–Source On–Voltage (V_{GS} = 10 Vdc, I_D = 3 Adc Per Side)	$V_{DS(on)}$	—	0.58	0.7	Vdc
Forward Transconductance (V_{DS} = 10 Vdc, I_D = 3 Adc Per Side)	g_{fs}	2.4	2.8	—	S
DYNAMIC CHARACTERISTICS (1)					
Input Capacitance (Per Side) (V_{DS} = 28 Vdc, V_{GS} = 0, f = 1 MHz)	C_{iss}	—	177	—	pF
Output Capacitance (Per Side) (V_{DS} = 28 Vdc, V_{GS} = 0, f = 1 MHz)	C_{oss}	—	45	—	pF
Reverse Transfer Capacitance (Per Side) (V_{DS} = 28 Vdc, V_{GS} = 0, f = 1 MHz)	C_{rss}	—	3.4	—	pF
FUNCTIONAL CHARACTERISTICS (In Motorola Test Fixture) **(2)**					
Two–Tone Common Source Amplifier Power Gain (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 960.0 MHz, f2 = 960.1 MHz)	G_{ps}	11	12.2	—	dB
Two–Tone Drain Efficiency (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 960.0 MHz, f2 = 960.1 MHz)	η	30	35	—	%
3rd Order Intermodulation Distortion (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 960.0 MHz, f2 = 960.1 MHz)	IMD	—	–32	–28	dBc
Input Return Loss (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 960.0 MHz, f2 = 960.1 MHz)	IRL	9	16	—	dB
Two–Tone Common Source Amplifier Power Gain (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 945.0 MHz, f2 = 945.1 MHz)	G_{ps}	—	12	—	dB
Two–Tone Drain Efficiency (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 945.0 MHz, f2 = 945.1 MHz)	η	—	33	—	%
3rd Order Intermodulation Distortion (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 945.0 MHz, f2 = 945.1 MHz)	IMD	—	–32	—	dBc
Input Return Loss (V_{DD} = 28 Vdc, P_{out} = 120 W PEP, I_{DQ} = 2 x 400 mA, f1 = 945.0 MHz, f2 = 945.1 MHz)	IRL	—	16	—	dB
Output Mismatch Stress (V_{DD} = 28 Vdc, P_{out} = 120 W CW, I_{DQ} = 2 x 400 mA, f = 960 MHz, VSWR = 5:1, All Phase Angles at Frequency of Tests)	Ψ	No Degradation In Output Power Before and After Test			

(1) Each side of device measured separately.
(2) Device measured in push–pull configuration.



B1 – B4	Fair Rite Products Short Ferrit Bead, 2743021446
C1, C7, C8, C10, C16, C17	10 µF, 50 V, Tantalum
C2, C11, C34, C35	0.1 µF, Chip Capacitor
C3, C6, C12, C15	330 pF, Chip Capacitor
C4, C5, C13, C14, C19, C20, C32, C33	47 pF, Chip Capacitor
C9, C18	250 µF, 50 V, Electrolytic Capacitor
C21, C22	12 pF, Chip Capacitor
C23, C30	0.6 – 4.5 pF, Variable Capacitor, Johanson Gigatrim
C24, C25, C26	5.1 pF, Chip Capacitor
C27, C28	3.9 pF, Chip Capacitor
C31	0.8 – 8.0 pF, Variable Capacitor, Johanson Gigatrim
L1, L2	3 Turns, #20 AWG, IDIA 0.126″, 24.7 nH
N1, N2	Type N Connectors
R1, R6	1 kΩ, 1/4 W, Carbon Resistor
R2, R5	1.2 kΩ, 0.1 W, Chip Resistor
R3, R4	75 Ω, 0.1 W, Chip Resistor
Z1 – Z22	Microstrip (See Component Placement)
Balun1, Balun2, Coax1, Coax2	2.20″ 50 Ω, 0.086″ OD Semi–Rigid Coax
Board	1/32″ Glass Teflon®, ε_r = 2.55

Figure 1. 930 – 960 MHz Test Circuit Schematic

TYPICAL CHARACTERISTICS

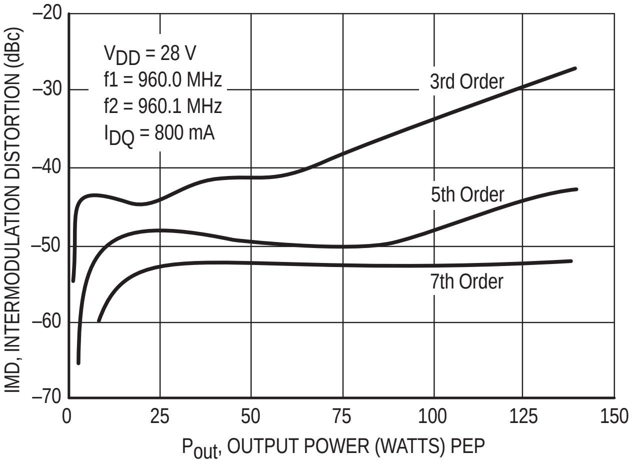


Figure 2. Intermodulation Distortion Products versus Output Power

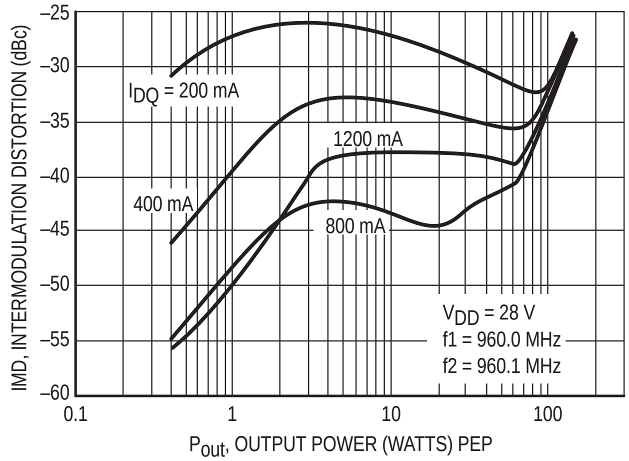


Figure 3. Intermodulation Distortion versus Output Power

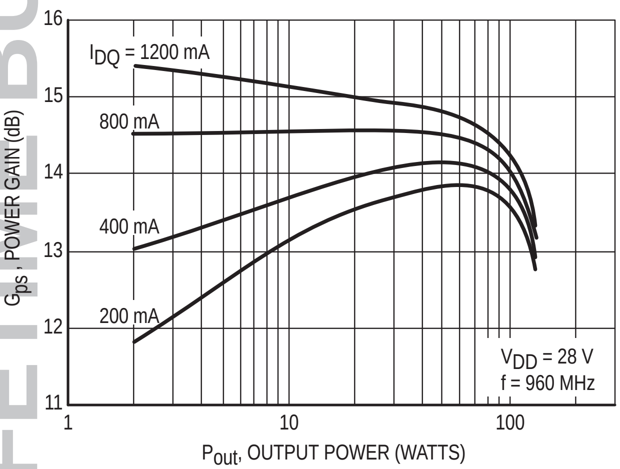


Figure 4. Power Gain versus Output Power

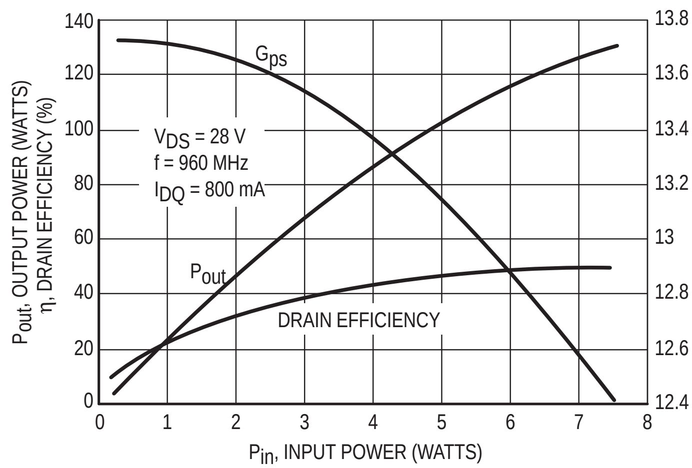


Figure 5. Output Power versus Input Power

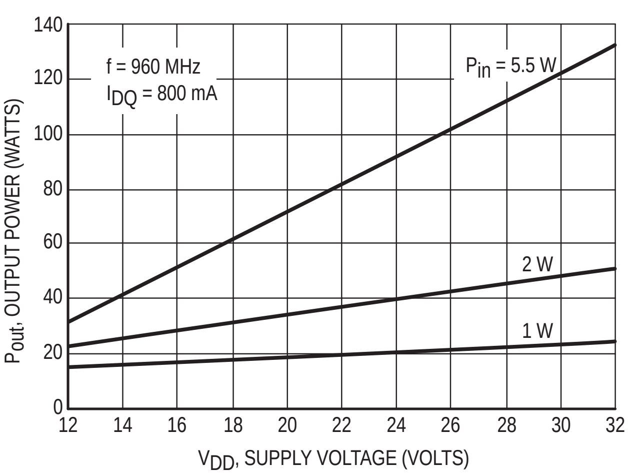


Figure 6. Output Power versus Supply Voltage

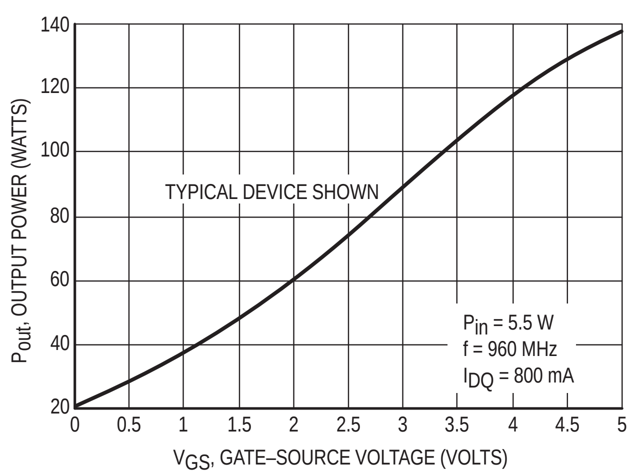


Figure 7. Output Power versus Gate Voltage

TYPICAL CHARACTERISTICS

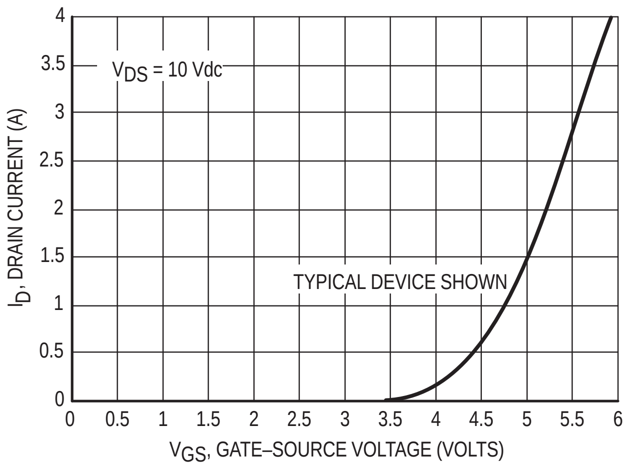


Figure 8. Drain Current versus Gate Voltage

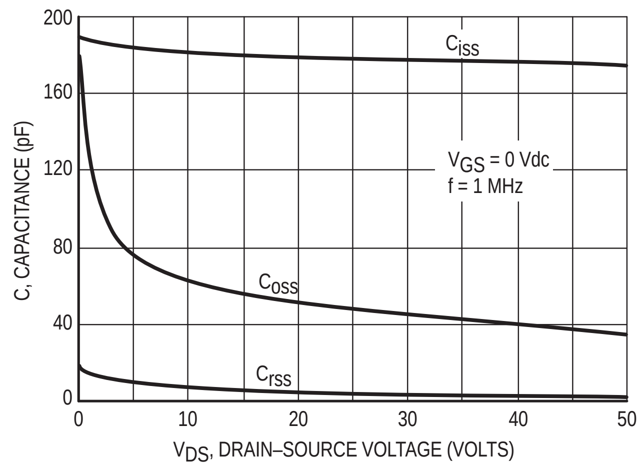


Figure 9. Capacitance versus Voltage

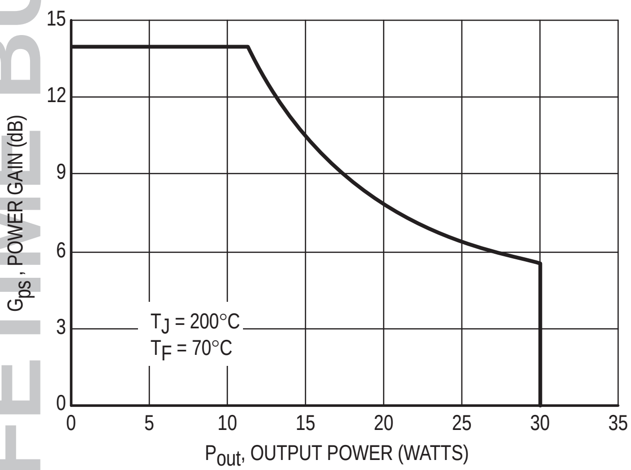


Figure 10. DC Safe Operating Area

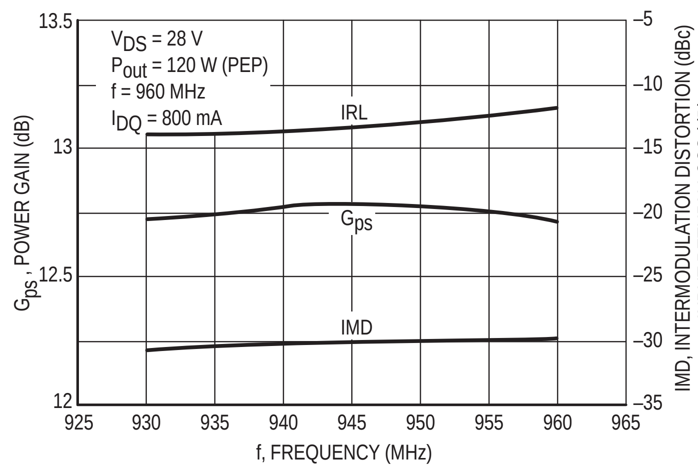
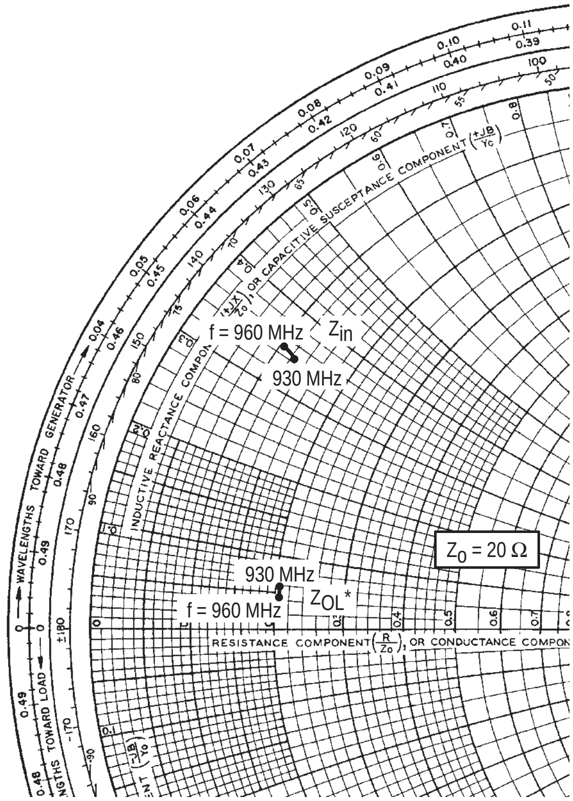


Figure 11. Broadband Circuit Performance



V_{CC} = 28 V, I_{DQ} = 2 × 400 mA, P_{out} = 120 Watts (PEP)

f MHz	Z_{in} Ω	Z_{OL}* Ω
930	2.5 + j6.9	4.3 + j1.2
945	2.5 + j7.0	4.3 + j1.0
960	2.2 + j7.1	4.3 + j0.9

Z_{in} = Complex conjugate of source impedance.

Z_{OL}* = Conjugate of the optimum load impedance at a given output power, voltage, IMD, bias current, efficiency and frequency.

Note: Z_{OL}* was chosen based on tradeoffs between gain, output power, drain efficiency and intermodulation performance. Impedances shown represent a single channel (1/2 of MRF186) impedance measurement.

Figure 12. Series Equivalent Input and Output Impedance

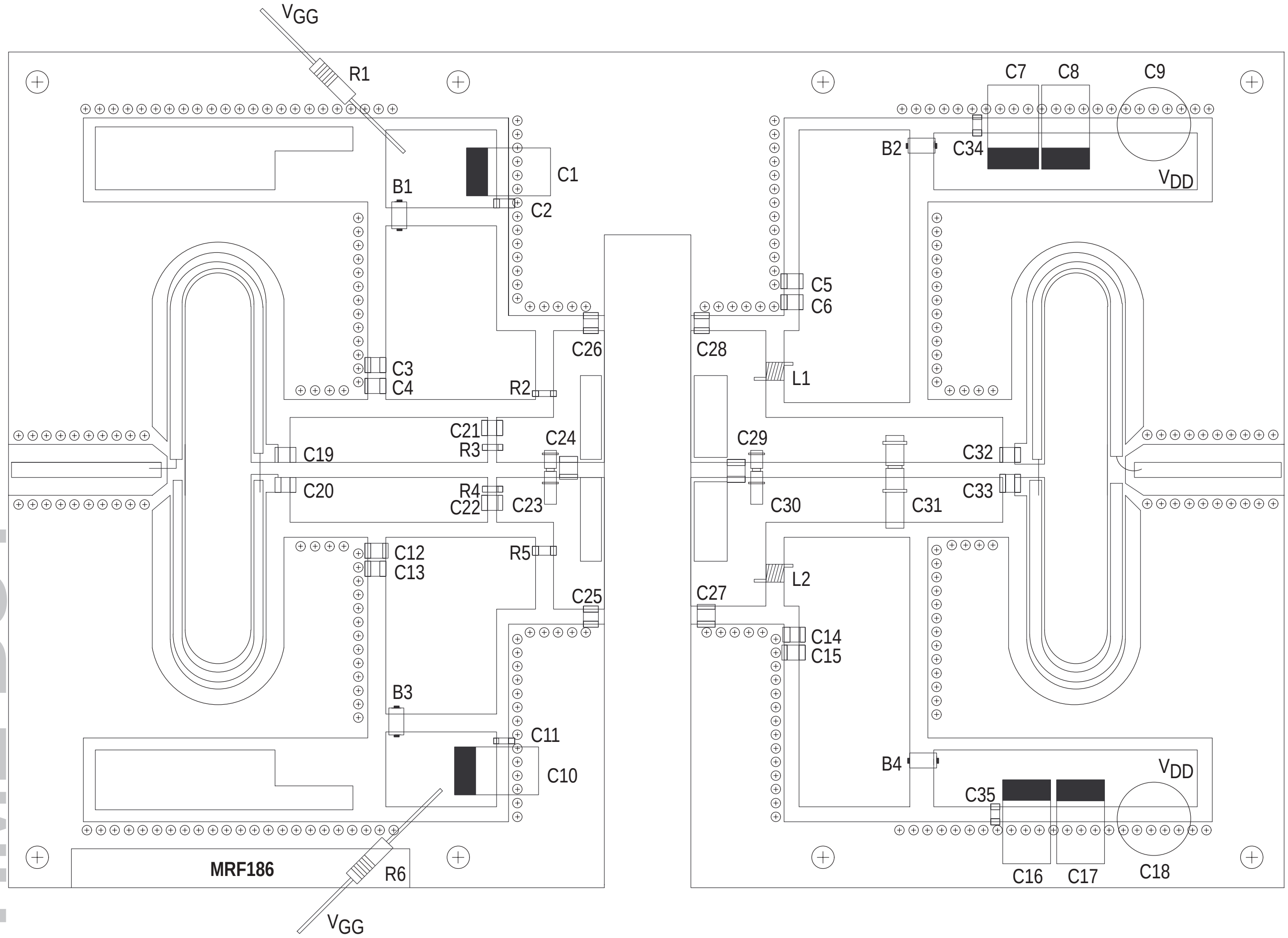
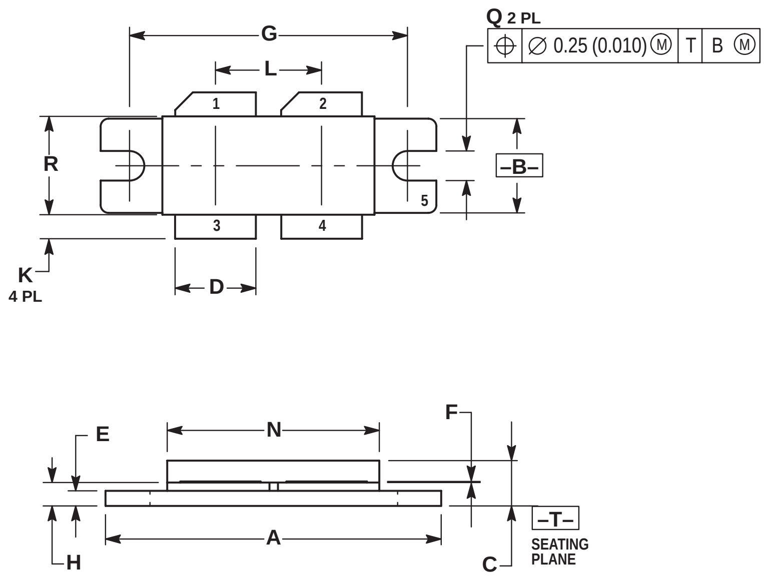


Figure 13. Component Placement Diagram of 930 – 960 MHz Broadband Test Fixture

PACKAGE DIMENSIONS



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.

DIM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	1.330	1.350	33.79	34.29
B	0.375	0.395	9.52	10.03
C	0.180	0.210	4.57	5.33
D	0.320	0.340	8.13	8.64
E	0.060	0.070	1.52	1.77
F	0.004	0.006	0.11	0.15
G	1.100 BSC		27.94 BSC	
H	0.093	0.108	2.36	2.74
K	0.085	0.115	2.16	2.92
L	0.425 BSC		10.80 BSC	
N	0.845	0.875	21.46	22.23
Q	0.118	0.130	3.00	3.30
R	0.390	0.410	9.91	10.41

STYLE 2:
PIN 1. DRAIN
2. DRAIN
3. GATE
4. GATE
5. SOURCE

CASE 375B–02
ISSUE A

How to reach us:
USA / EUROPE / Locations Not Listed: Motorola Literature Distribution;
P.O. Box 5405, Denver, Colorado 80217. 1–303–675–2140 or 1–800–441–2447

Customer Focus Center: 1–800–521–6274

Mfax™: RMFAX0@email.sps.mot.com – TOUCHTONE 1–602–244–6609
Motorola Fax Back System – US & Canada ONLY 1–800–774–1848
– http://sps.motorola.com/mfax/

HOME PAGE: http://motorola.com/sps/

JAPAN: Motorola Japan Ltd.; SPD, Strategic Planning Office, 141,
4–32–1 Nishi–Gotanda, Shinagawa–ku, Tokyo, Japan. 81–3–5487–8488

ASIA / PACIFIC: Motorola Semiconductors H.K. Ltd.; Silicon Harbour Centre,
2, Dai King Street, Tai Po Industrial Estate, Tai Po, N.T., Hong Kong.
852–26668334